Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/541,384	TAKEI ET AL.	
Examiner	Art Unit	

Nam Huynh

2617

SEARCHED				
Class	Subclass	Date	Examiner	
455	412.2	9/20/2006	NTH	
	3.03			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		·		

(INCLUDING SEAR	CH STRATEGY	<u>') </u>
	DATE	EXMR
See EAST search notes.	9/20/2006	NTH